

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Applicant(s): Akira HAMAMATSU, et al  
Serial No.: (not yet assigned)  
Filed: December 2, 2003  
For: METHOD FOR INSPECTING DEFECT AND APPARATUS FOR  
INSPECTING DEFECT

**INFORMATION DISCLOSURE STATEMENT**  
**UNDER 37 CFR 1.97 & 1.98**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

December 2, 2003

Sir:

In the matter of the above-identified application, this information disclosure statement is being submitted with the following citation as specified in 37 CFR 1.97(d).

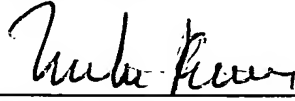
"A copy of any patent, publication or other information listed in an information disclosure statement is not required to be provided if it was previously cited by or submitted to the Office in a prior application, provided that the prior application is properly identified in the statement and relied upon for an earlier filing date under 35 U.S.C. 120."

Applicant(s) are submitting herewith a copy of Form PTO-1449 which list documents cited in parent application(s) Serial No. , filed November 28, 2003, by the inventors Akira Hamamatsu, Minoru Noguchi, Hidetoshi Nishiyama, Yoshimasa Ohshima, Takahiro Jingu, and Sachio Uto, under the title "INSPECTION METHOD AND INSPECTION APPARATUS".

It is respectfully requested that this information disclosure statement be considered by the Examiner.

Please charge any shortage in the fees due in connection with the filing of this paper, including extension of time fees, to Deposit Account No. 01-2135 (520.43302PX1) and please credit any excess fees to such deposit account.

Respectfully submitted,



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Form PTO-1449  
Equivalent

U.S. Department of Commerce  
Patent and Trademark Office

Atty. Docket No. 520.43302PX1  
Serial No. (not yet assigned)  
Applicant: HAMAMATSU, et al  
Filing Date: December 2, 2003  
Group:

U.S. Patent Documents

Examiner Initials	Document No.	Date	Name	Class Subclass	Filing Date If Approp.
	6,411,377 B1	06/25/02	Noguchi		July 28, 1999

Foreign Patent Documents

Document No.	Date	Country	Class Subclass	Translation Yes No
62-089336	04/23/87	JP		X
1-117024	05/09/89	JP		X
1-250847	10/05/89	JP		X
5-218163	8/27/93	JP		X
6-258239	9/16/94	JP		X
6-324003	11/25/94	JP		X
8-210989	8/20/96	JP		X
2000-105203	4/11/00	JP		X

Other Documents (including Author, Title, Date, Pertinent Pages, etc.)

Examiner

Date Considered

\*Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609;  
Draw line through citation if not in conformance and not considered. Include copy of this form with next  
communication to applicant.